

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Joachim STUMPE et al.

International Appln: PCT/EP2004/005911
Filed: June 1, 2003

U.S. Application No.: Not Yet Assigned

For: METHOD AND DEVICE FOR
THREE-DimensionALLY
DETERMINING THE REFRACTIVE
INDEX OF TRANSPARENT OR
PARTIALLY TRANSPARENT
LAYERS

Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned

Confirmation No.: Not Yet Assigned

Atty. Docket No.: 31583-226294 RK

Customer No.: 26694

Information Disclosure Statement

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This is an Information Disclosure Statement submitted under 37 C.F.R. § 1.97 within the time specified under 37 C.F.R. § 1.97(c).

In order to comply the duty of disclosure pursuant to 37 C.F.R. § 1.56, submitted herewith is a Form PTO/SB/08A listing the documents cited in the international application and in the International Search Report of International Application No. PCT/EP2004/005911. The relevance of each document is indicated therein.

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Applicant(s): Joachim STUMPE et al.
Atty. Docket: 31583-226294 RK

In view of the above, no further statement of relevance need be given, and as all requirements of 37 C.F.R. § 1.97 and § 1.98, and all official guidelines pertaining to Information Disclosure Statements have been complied with, it is respectfully requested that the Examiner consider the cited publications and make them of record.

Respectfully submitted,

Date: December 5, 2005


Robert Kinberg
Registration No. 26,924
VENABLE LLP
P.O. Box 34385
Washington, D.C. 20043-9998
Telephone: (202) 344-4000
Telefax: (202) 344-8300

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>		Complete if Known	
		Application Number	NOT YET ASSIGNED
		Filing Date	Concurrently
		First Named Inventor	Joachim STUMPE et al.
		Group Art Unit	Not Yet Assigned
		Examiner Name	Not Yet Assigned
		Attorney Docket Number	31583-226294 RK

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	AF	RAMSDALE et al., "Ellipsometric Determination of Anisotropic Optical Constants In Electroluminescent Conjugated Polymers", Advanced Materials, VCH, Verlagsgesellschaft, Weinheim, DE, vol. 14, no. 3, 5 February 2002, pp. 212-215	
	AG	BORTCHAGOVSKY E.G., "Ellipsometric Method for Investigation of the Optical Anisotropy of Thin Films: Theory and Calculations", Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH, vol. 307, No. 1-2, 10 October 1997, pages 192-199	
	AH	T. SRIKHIRINM, "An Investigation of the Photoinduced Changes of Absorption of High-Performance Photoaddressable Polymers", Chemphyschem, vol. 3, 2002, pp. 335-345	
	AI	BORTCHAGOVSKY E.G. et al., "Comparison of Ellipsometric Methods for Separate Determination of Thickness and Optical Constants of Thin Films", Folia Biologica, vol. 4517, 5 June 2000, pp. 126-133	
	AJ	JUNG C.C. et al., "Three Dimensional Anisotropies Induced by Light In Thin Polymer Films", Proc. Spei - Int. Soc. Opt. Eng. (USA), "Proceedings of The Spei - The International Society for Optical Engineering, 2003, Spei-Int. Soc. Opt. Eng. USA, vol. 5212, no. 1, 4 August 2003, pp. 83-93	
	AK	Patent Abstracts of Japan, vol. 1999, No. 05, 31 May 1999	
	AL	Patent Abstracts of Japan, vol. 015, No. 460, 21 November 1991	

Examiner Signature		Date Considered	
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² Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.

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